

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09925397	CHANG ET AL.
	Examiner	Art Unit
	Ehichioya, Fred I	2162

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
IEEE Xplore	12/16/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	6/24/08	FE
Google.com	6/24/08	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	2/23/2009	FE
Google Search	2/20/2009	FE

### INTERFERENCE SEARCH

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